December 2005

FDMB506P

## FDMB506P

FAIRCHILD Semiconductor

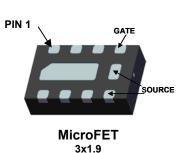
## P-Channel 1.8V Logic Level PowerTrench<sup>®</sup> MOSFET

### **General Description**

This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance. These devices are well suited for portable electronics applications.

### Applications

- Load switch
- DC/DC Conversion

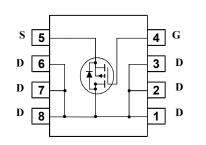


## Features

• -6.8 A, -20V.  $R_{DS(ON)} = 30 \text{ m}\Omega \textcircled{0} V_{GS} = -4.5 V$  $R_{DS(ON)} = 38 \text{ m}\Omega \textcircled{0} V_{GS} = -2.5 V$  $R_{DS(ON)} = 70 \text{ m}\Omega \textcircled{0} V_{GS} = -1.8 V$ 

- Low profile 0.8 mm maximum
- Fast switching
- RoHS compliant



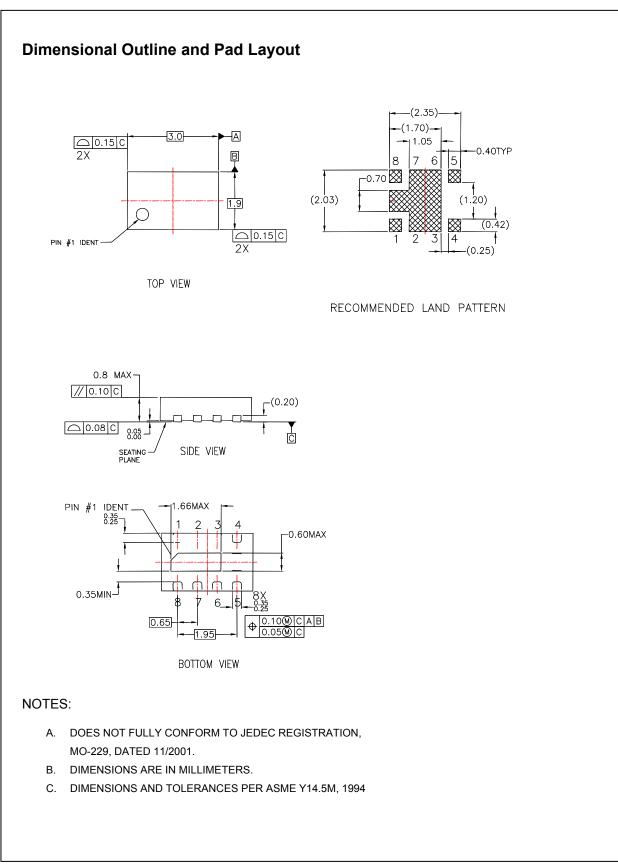


### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

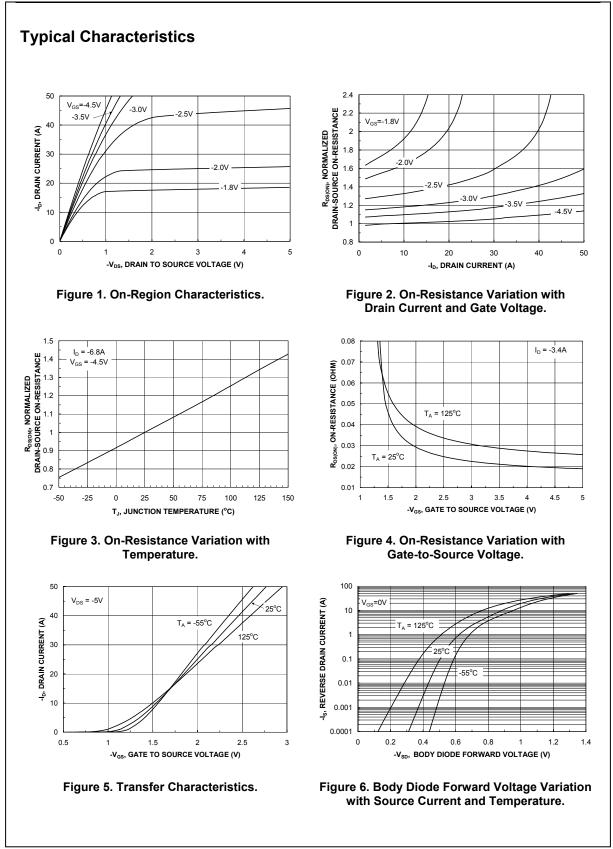
Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage			-20	V
V <sub>GSS</sub>	Gate-Source Voltage			±8	
ID	Drain Current – Continuous (Note 1a)		(Note 1a)	-6.8	А
	– Pulsed			70	
PD	Power Diss	ipation	(Note 1a)	1.9	
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range			–55 to +150	°C
Therma R <sub>0JA</sub>	1	cteristics	mbient (Note 1a)	65	°C/W
R <sub>0JA</sub>	Thermal Resistance, Junction-to-Ambient (Note 1b)			208	
Package Markin Device Marking 506		ng and Orderin Device	g Information Reel Size	Tape width	Quantity
	-	FDMB506P	7"	8mm	3000 units

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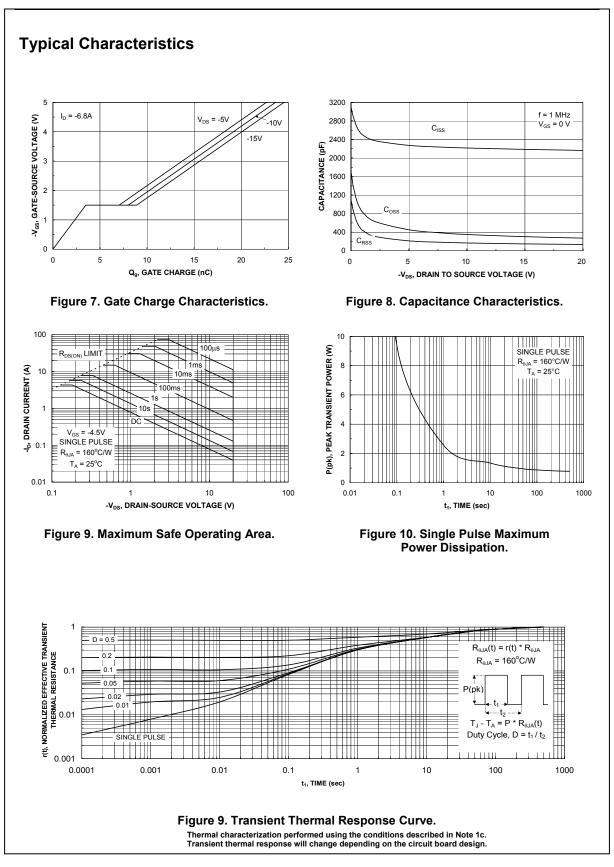
istics -Source Breakdown Voltage down Voltage Temperature icient Gate Voltage Drain Current -Body Leakage istics (Note 2) Threshold Voltage Threshold Voltage	$\begin{array}{l} V_{GS} = 0 \ V, & I_{D} = -250 \ \mu A \\ I_{D} = -250 \ \mu A, \ \text{Referenced to } 25^{\circ}\text{C} \\ \end{array}$ $\begin{array}{l} V_{DS} = -16 \ V, & V_{GS} = 0 \ V \\ V_{GS} = \pm 8 \ V, & V_{DS} = 0 \ V \\ \end{array}$ $\begin{array}{l} V_{DS} = V_{GS}, & I_{D} = -250 \ \mu A \end{array}$	-20	-13	-1 ±100	V mV/°C μA nA
-Source Breakdown Voltage down Voltage Temperature icient Gate Voltage Drain Current -Body Leakage istics (Note 2) Threshold Voltage	$I_{D} = -250 \ \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -16 \ \text{V},  V_{GS} = 0 \ \text{V}$ $V_{GS} = \pm 8 \ \text{V},  V_{DS} = 0 \ \text{V}$	-20	-13		mV/°C μA
kdown Voltage Temperature icient Gate Voltage Drain Current -Body Leakage istics (Note 2) Threshold Voltage	$I_{D} = -250 \ \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -16 \ \text{V},  V_{GS} = 0 \ \text{V}$ $V_{GS} = \pm 8 \ \text{V},  V_{DS} = 0 \ \text{V}$		-13		μA
-Body Leakage istics (Note 2) Threshold Voltage	$V_{GS} = \pm 8 V$ , $V_{DS} = 0 V$				•
istics (Note 2) Threshold Voltage	$V_{GS} = \pm 8 V$ , $V_{DS} = 0 V$			±100	nA
Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = -250 \ \mu A$	_			
Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$				
Threshold Voltage		-0.4	-0.7	-1.5	V
erature Coefficient	$I_D = -250 \ \mu$ A, Referenced to 25°C		3		mV/°C
Drain–Source Resistance	$ \begin{array}{l} V_{GS} = -4.5 \ V,  I_D = -6.8 \ A \\ V_{GS} = -2.5 \ V,  I_D = -2.5 \ A \\ V_{GS} = -1.8 \ V,  I_D = -1.8 \ A \\ V_{GS} = -4.5 \ V, \ I_D = -6.8 \ A, \ T_J = 125^\circ C \end{array} $		25 30 40 36	30 38 70 44	mΩ
ard Transconductance	$V_{DS} = -5 V$ , $I_{D} = -6.8 A$		26		s
racteristics					
	$V_{DS} = -10 V$ , $V_{CS} = 0 V$ .		2216	2960	pF
ut Capacitance	f = 1.0 MHz		351	470	pF
rse Transfer Capacitance	1		167	260	pF
aracteristics (Note 2)			1		
	$V_{DD} = -10 V$ . $I_D = -1 A$ .		14	25	ns
,	$V_{GS} = -4.5 \text{ V},  R_{GEN} = 6 \Omega$		8	16	ns
			175	280	ns
-Off Fall Time	1		80	128	ns
Gate Charge	$V_{DS} = -10 V$ , $I_D = -6.8 A$ ,		21	30	nC
-Source Charge	$V_{GS} = -4.5 V$		3.5		nC
-Drain Charge	1		4.5		nC
Diode Characteristics	and Maximum Ratings				
				1.6	А
	$V_{GS} = 0 V$ , $I_{S} = -0.8 A$ (Note 2)		-0.6	-1.2	V
e Reverse Recovery Time	$I_{\rm F} = -6.8  {\rm A},$		26	48	nS
e Reverse Recovery Charge	d <sub>i</sub> ⊧/d <sub>t</sub> = 100 A/µs		12	22	nC
	num Continuous Drain–Source –Source Diode Forward ge e Reverse Recovery Time e Reverse Recovery Charge f the junction-to-case and case-to-ambie	$V_{GS} = -1.8 \text{ V},  I_D = -1.8 \text{ A} \\ V_{GS} = -4.5 \text{ V},  I_D = -6.8 \text{ A},  T_J = 125^{\circ}\text{C}$ ard Transconductance $V_{DS} = -5 \text{ V},  I_D = -6.8 \text{ A}$ <b>racteristics</b> $Capacitance \qquad V_{DS} = -10 \text{ V},  V_{GS} = 0 \text{ V},  f = 1.0 \text{ MHz}$ rese Transfer Capacitance $aracteristics  (Note 2)$ -On Delay Time $-On \text{ Diagy Time} \qquad V_{DD} = -10 \text{ V},  I_D = -1 \text{ A},  V_{GS} = -4.5 \text{ V},  R_{GEN} = 6 \Omega$ -Off Delay Time $-Off \text{ Fall Time} \qquad V_{DS} = -10 \text{ V},  I_D = -6.8 \text{ A},  V_{GS} = -4.5 \text{ V}$ -Source Charge $-Drain \text{ Charge} \qquad V_{DS} = -10 \text{ V},  I_D = -6.8 \text{ A},  V_{GS} = -4.5 \text{ V}$ $Diode Characteristics and Maximum Ratings$ num Continuous Drain–Source Diode Forward Current $-Source \text{ Diode Forward} \qquad V_{GS} = 0 \text{ V},  I_S = -0.8 \text{ A}(\text{Note 2})$ $e \text{ Reverse Recovery Time} \qquad I_F = -6.8 \text{ A},  d_{iF}/d_t = 100 \text{ A}/\mu \text{ s}$	$V_{GS} = -1.8 \text{ V}, I_D = -1.8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.8 \text{ A}, T_J = 125 °C$ ard Transconductance $V_{DS} = -5 \text{ V}, I_D = -6.8 \text{ A}$ racteristicsCapacitance $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ art Capacitance $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ art Capacitance $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ aracteristics (Note 2)-On Delay Time $V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$ On Rise Time $V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$ Off Fall Time $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$ Off Fall Time $V_{DS} = -10 \text{ V}, I_D = -6.8 \text{ A},$ -Order Charge $V_{GS} = -4.5 \text{ V}$ -Drain Charge $V_{GS} = -4.5 \text{ V}$ Diode Characteristics and Maximum Ratingsnum Continuous Drain-Source Diode Forward Current-Source Diode Forward $V_{GS} = 0 \text{ V}, I_S = -0.8 \text{ A}(Note 2)$ $ge$ $e$ Reverse Recovery Time $I_F = -6.8 \text{ A},$ $e$ Reverse Recovery Charge $I_F = -0.8 \text{ A},$ $d_{IF}/d_t = 100 \text{ A}/\mu \text{ S}$	$V_{GS} = -1.8 \text{ V}, I_D = -1.8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.8 \text{ A}, T_J = 125 ^{\circ}\text{C}$ 40 36ard Transconductance $V_{DS} = -5 \text{ V}, I_D = -6.8 \text{ A}$ 26racteristicsCapacitance $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ 2216it Capacitancef = 1.0 \text{ MHz}351rse Transfer Capacitance167aracteristics (Note 2)-On Delay Time $V_{DD} = -10 \text{ V}, I_D = -1 \text{ A}, V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$ -Off Delay Time $V_{DS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$ -Off Fall Time80Gate Charge $V_{DS} = -10 \text{ V}, I_D = -6.8 \text{ A}, V_{GS} = -4.5 \text{ V}$ -Source Charge $V_{GS} = -4.5 \text{ V}$ -Drain Charge $V_{GS} = -10 \text{ V}, I_D = -6.8 \text{ A}, V_{GS} = -4.5 \text{ V}$ -Diode Characteristics and Maximum Ratingsnum Continuous Drain–Source Diode Forward Current-Source Diode Forward-Source Diode Forward $V_{GS} = 0 \text{ V}, I_S = -0.8 \text{ A}(Note 2)$ -0.6gea Reverse Recovery Time $I_F = -6.8 \text{ A}, d_F/d_t = 100 \text{ A}/\mu \text{ S}$ $I_F$ $I_F$ the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder m	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$



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